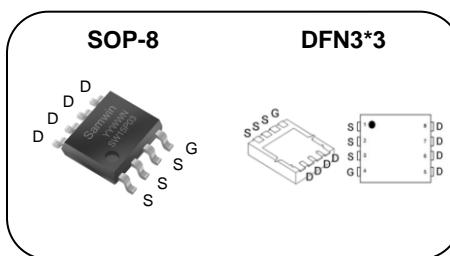


P-channel Enhanced mode SOP-8/DFN3*3 MOSFET

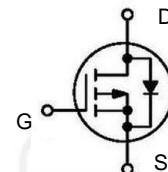
Features

- High ruggedness
- Low $R_{DS(ON)}$ (Typ 14mΩ)@ $V_{GS}=-4.5V$
- Low $R_{DS(ON)}$ (Typ 10mΩ)@ $V_{GS}=-10V$
- Low Gate Charge (Typ 48nC)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Application: Adaptor Input Switch for Notebook PC



SOP-8/DFN3*3: 4.Gate 5,6,7,8.Drain 1,2,3.Source

BV_{DSS} : -30V
 I_D : -15A
 $R_{DS(ON)}$: 14mΩ @ $V_{GS}=-4.5V$
 10mΩ @ $V_{GS}=-10V$



General Description

This power MOSFET is produced with advanced technology of SAMWIN. This technology enable the power MOSFET to have better characteristics, including Fast switching time, low on resistance, low gate charge and especially excellent Avalanche characteristics.

Order Codes

Item	Sales Type	Marking	Package	Packaging
1	SW K 15P03	SW15P03	SOP-8	REEL
2	SW H 15P03	SW15P03	DFN3*3	REEL

Absolute maximum ratings

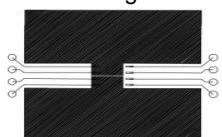
Symbol	Parameter	Value		Unit
		SOP-8	DFN3*3	
V_{DSS}	Drain to source voltage	-30		V
I_D	Continuous drain current (@ $T_C=25^\circ C$)	-15*		A
	Continuous drain current (@ $T_C=100^\circ C$)	-9.5*		A
I_{DM}	Drain current pulsed (note 1)	-60		A
V_{GS}	Gate to source voltage	± 25		V
E_{AS}	Single pulsed avalanche energy (note 2)	81		mJ
dv/dt	Peak diode recovery dv/dt (note 3)	5		V/ns
P_D	Total power dissipation (@ $T_a=25^\circ C$)	2.5	2.1	W
	Derating factor above 25°C	0.02	0.017	W/°C
T_{STG}, T_J	Operating junction temperature & storage temperature	-55 ~ + 150		°C

*. Drain current is limited by junction temperature.

Thermal characteristics

Symbol	Parameter	Value		Unit
		SOP-8	DFN3*3	
R_{thja}	Thermal resistance, Junction to ambient (note)	50	60	°C/W

Note: R_{thja} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{thjc} is guaranteed by design while R_{thca} is determined by the user's board design.



SOP-8 : 50°C/W on a 1 in² pad of 2oz copper.

DFN3*3 : 60°C/W on a 1 in² pad of 2oz copper.

Electrical characteristic ($T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
Off characteristics						
BV_{DSS}	Drain to source breakdown voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-30			V
$\Delta \text{BV}_{\text{DSS}} / \Delta T_J$	Breakdown voltage temperature coefficient	$I_{\text{D}}=-250\mu\text{A}$, referenced to 25°C		0.02		$\text{V}/^\circ\text{C}$
I_{DSS}	Drain to source leakage current	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}$			-1	μA
		$V_{\text{DS}}=-24\text{V}, T_C=125^\circ\text{C}$			-50	μA
I_{GSS}	Gate to source leakage current, forward	$V_{\text{GS}}=-25\text{V}, V_{\text{DS}}=0\text{V}$			-100	nA
	Gate to source leakage current, reverse	$V_{\text{GS}}=25\text{V}, V_{\text{DS}}=0\text{V}$			100	nA
On characteristics						
$V_{\text{GS(TH)}}$	Gate threshold voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-1		-2.5	V
$R_{\text{DS(ON)}}$	Drain to source on state resistance	$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-7.5\text{A}$		14	22	$\text{m}\Omega$
		$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-7.5\text{A}$		10	14	$\text{m}\Omega$
G_{fs}	Forward transconductance	$V_{\text{DS}}=-10\text{V}, I_{\text{D}}=-7.5\text{A}$		29		S
Dynamic characteristics						
C_{iss}	Input capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=-15\text{V}, f=1\text{MHz}$		3290		pF
C_{oss}	Output capacitance			344		
C_{rss}	Reverse transfer capacitance			277		
$t_{\text{d(on)}}$	Turn on delay time	$V_{\text{DS}}=-15\text{V}, I_{\text{D}}=-15\text{A}, R_G=25\Omega$, $V_{\text{GS}}=-10\text{V}$ (note 4,5)		15		ns
t_r	Rising time			90		
$t_{\text{d(off)}}$	Turn off delay time			214		
t_f	Fall time			150		
Q_g	Total gate charge	$V_{\text{DS}}=-24\text{V}, V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-15\text{A}$ (note 4,5)		48		nC
Q_{gs}	Gate-source charge			7		
Q_{gd}	Gate-drain charge			10		
R_g	Gate resistance	$V_{\text{DS}}=0\text{V}$, Scan F mode		14		Ω

Source to drain diode ratings characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_s	Continuous source current	Integral reverse p-n Junction diode in the MOSFET			-15	A
I_{SM}	Pulsed source current				-60	A
V_{SD}	Diode forward voltage drop.	$I_s=-15\text{A}, V_{\text{GS}}=0\text{V}$			-1.4	V
t_{rr}	Reverse recovery time	$I_s=-15\text{A}, V_{\text{GS}}=0\text{V}$, $dI_F/dt=100\text{A/us}$		17		ns
Q_{rr}	Reverse recovery charge			3.5		nC

※. Notes

1. Repetitive rating : pulse width limited by junction temperature.
2. $L = 4.5\text{mH}$, $I_{\text{AS}} = -6\text{A}$, $V_{\text{DD}} = -25\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{\text{SD}} \leq -15\text{A}$, $dI/dt = 100\text{A/us}$, $V_{\text{DD}} \leq \text{BV}_{\text{DSS}}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse Width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
5. Essentially independent of operating temperature.

Fig. 1. On-state characteristics

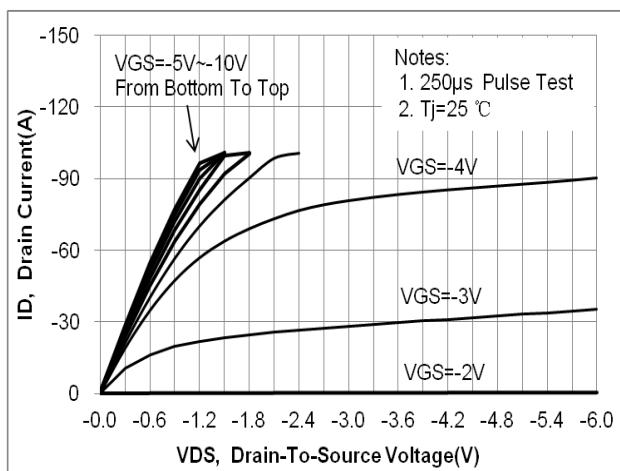


Fig. 2. On-resistance variation vs. drain current and gate voltage

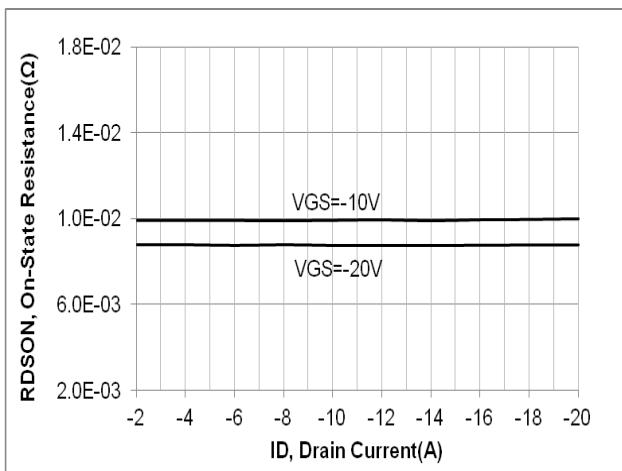


Fig. 3. Gate charge characteristics

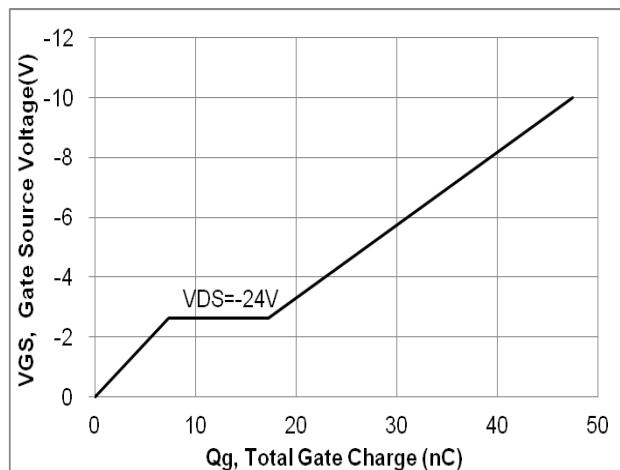


Fig. 4. On state current vs. diode forward voltage

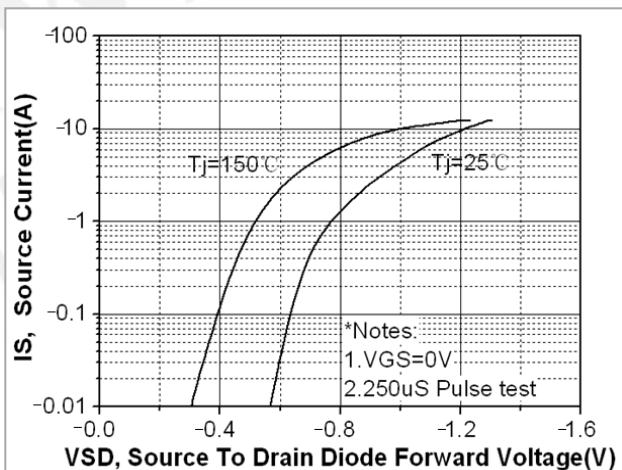


Fig 5. Breakdown Voltage Variation vs. Junction Temperature

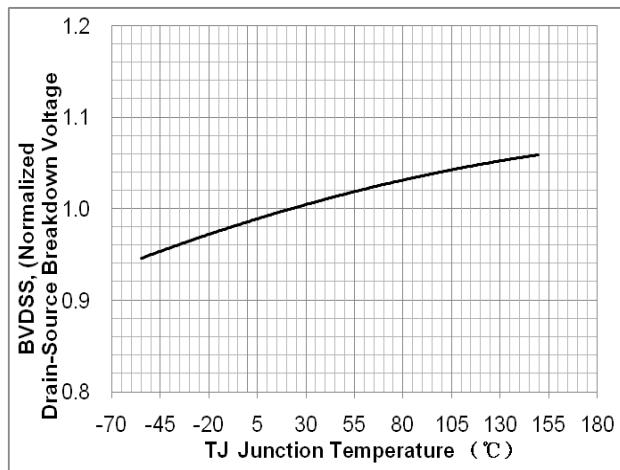


Fig. 6. On resistance variation vs. junction temperature

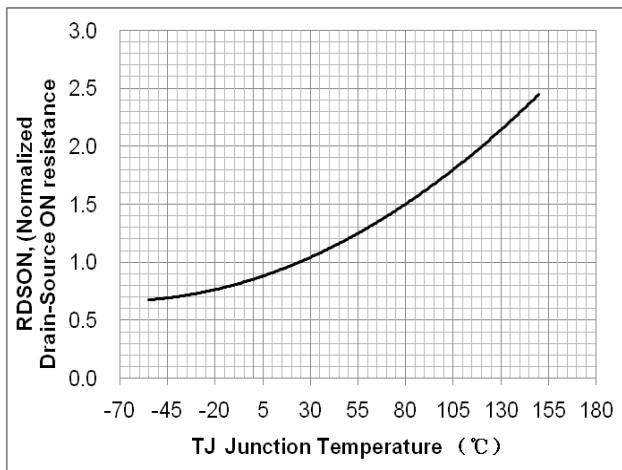


Fig. 7. Capacitance Characteristics

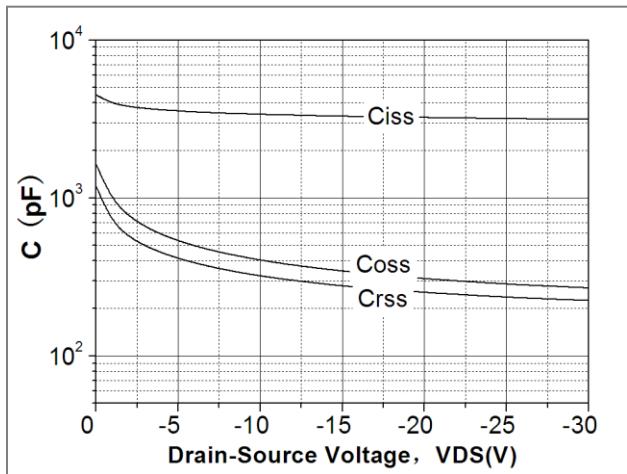


Fig. 8. Maximum safe operating area (SOP-8)

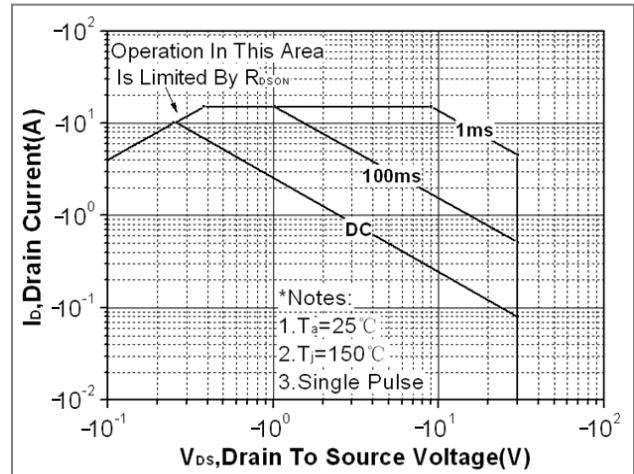


Fig. 9. Maximum safe operating area (DFN3*3)

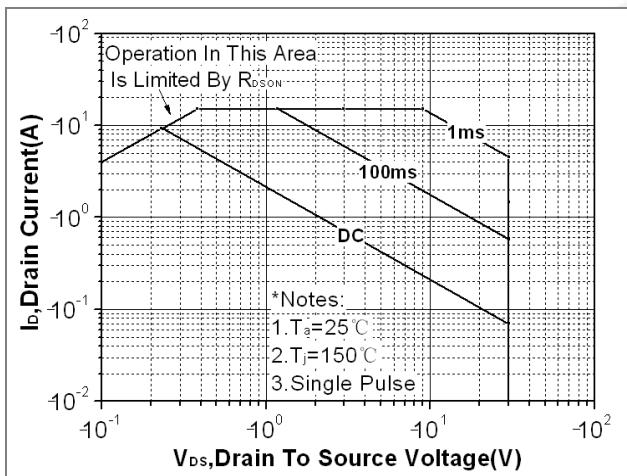


Fig. 10. Transient thermal response curve (SOP-8)

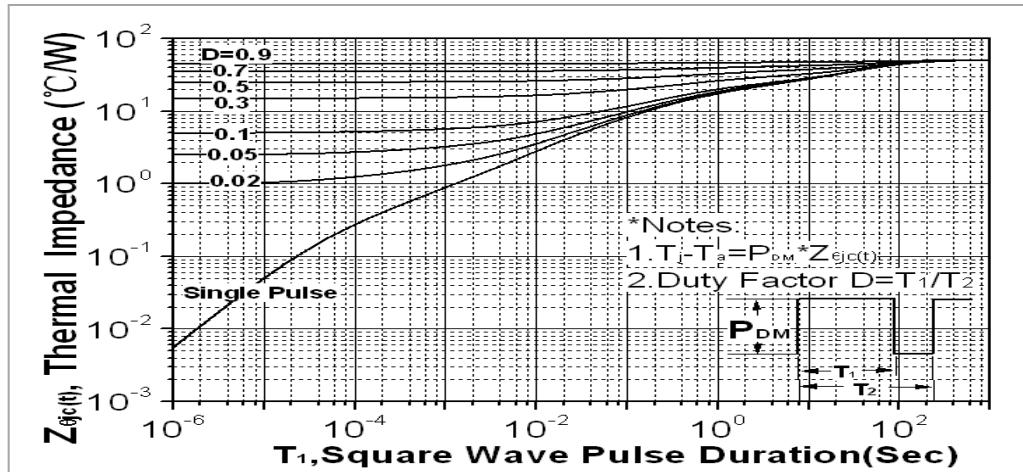


Fig. 11. Transient thermal response curve (DFN3*3)

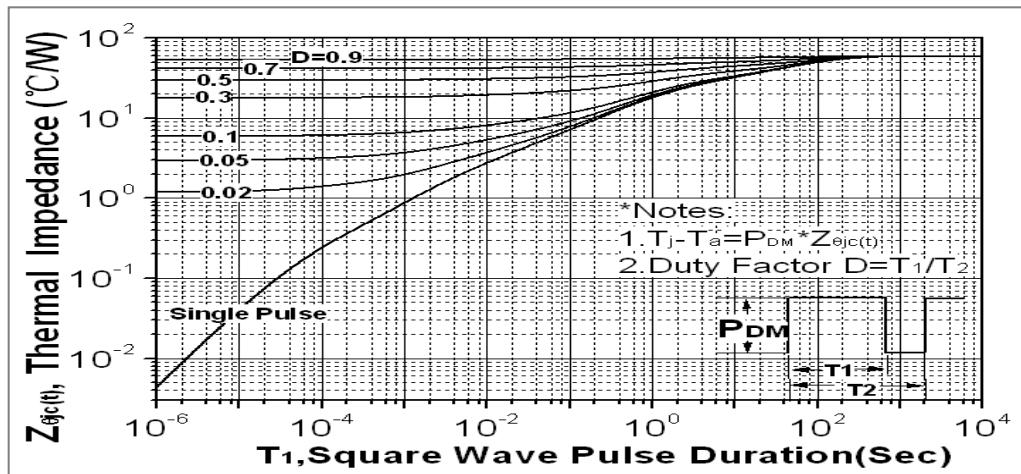


Fig. 12. Gate charge test circuit & waveform

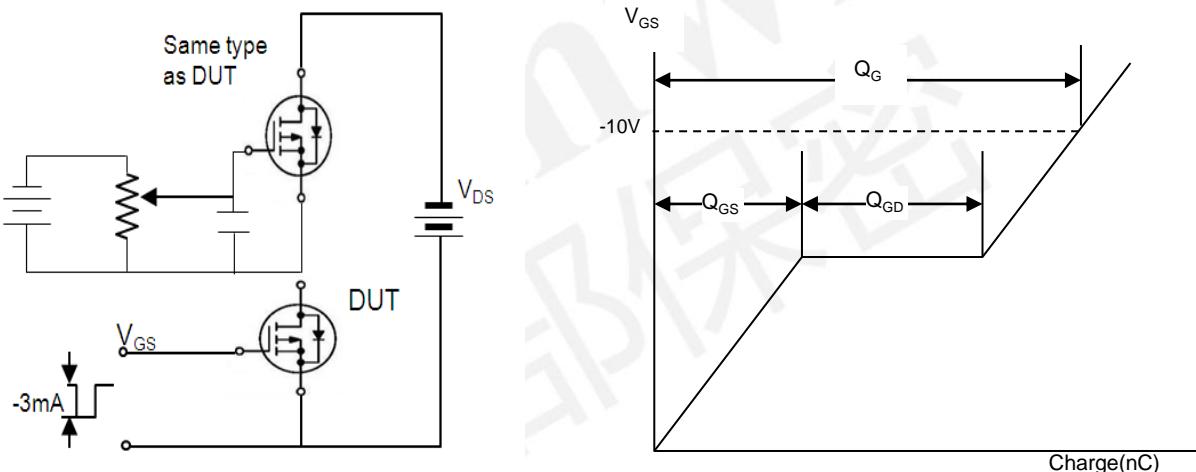


Fig. 13. Switching time test circuit & waveform

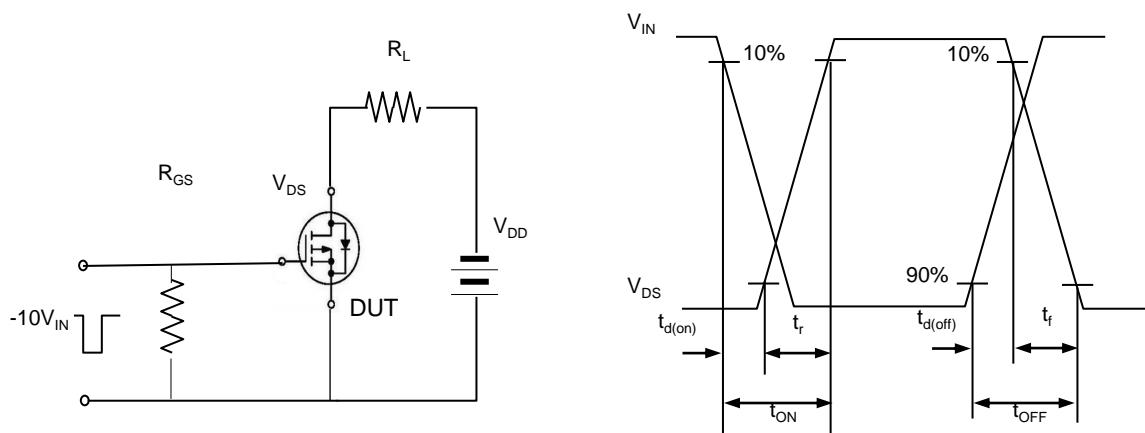


Fig. 14. Unclamped Inductive switching test circuit & waveform

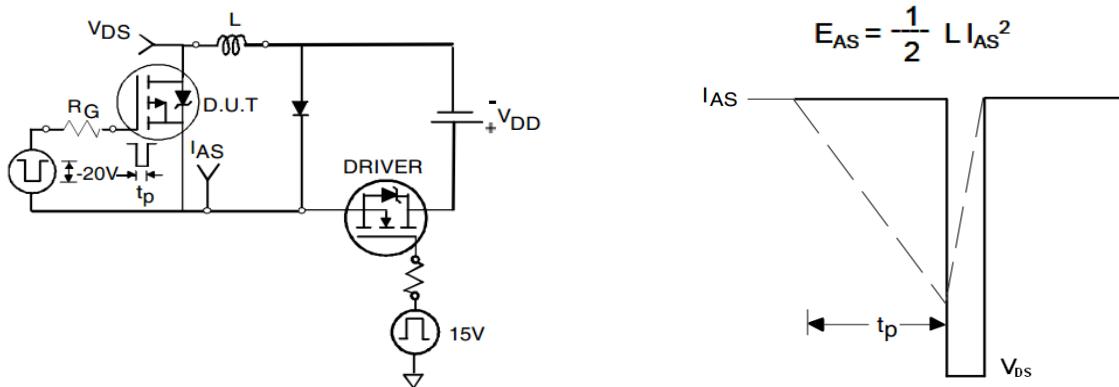
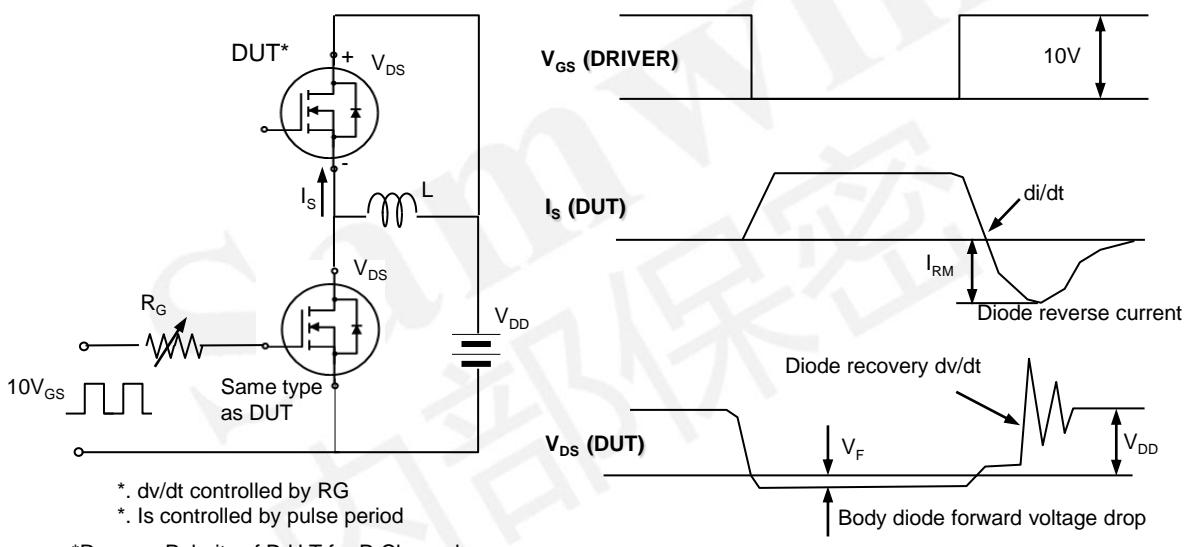


Fig. 15. Peak diode recovery dv/dt test circuit & waveform



DISCLAIMER

- * All the data & curve in this document was tested in XI' AN SEMIPOWER TESTING & APPLICATION CENTE R.
- * This product has passed the PCT, TC, HTRB, HTGB, HAST, PC and Solderdunk reliability testing.
- * Qualification standards can also be found on the Web site (<http://www.semipower.com.cn>)
- * Suggestions for improvement are appreciated, Please send your suggestions to samwin@ samwinsemi.com

X-ON Electronics

Largest Supplier of Electrical and Electronic Components

Click to view similar products for MOSFET category:

Click to view products by Sam&wing manufacturer:

Other Similar products are found below :

[614233C](#) [648584F](#) [MCH3443-TL-E](#) [MCH6422-TL-E](#) [FDPF9N50NZ](#) [FW216A-TL-2W](#) [FW231A-TL-E](#) [APT5010JVR](#) [NTNS3A92PZT5G](#)
[IRF100S201](#) [JANTX2N5237](#) [2SK2464-TL-E](#) [2SK3818-DL-E](#) [FCA20N60_F109](#) [FDZ595PZ](#) [STD6600NT4G](#) [FSS804-TL-E](#) [2SJ277-DL-E](#)
[2SK1691-DL-E](#) [2SK2545\(Q,T\)](#) [D2294UK](#) [405094E](#) [423220D](#) [MCH6646-TL-E](#) [TPCC8103,L1Q\(CM](#) [367-8430-0972-503](#) [VN1206L](#)
[424134F](#) [026935X](#) [051075F](#) [SBVS138LT1G](#) [614234A](#) [715780A](#) [NTNS3166NZT5G](#) [751625C](#) [873612G](#) [IRF7380TRHR](#)
[IPS70R2K0CEAKMA1](#) [RJK60S3DPP-E0#T2](#) [RJK60S5DPK-M0#T0](#) [APT5010JVFR](#) [APT12031JFLL](#) [APT12040JVR](#) [DMN3404LQ-7](#)
[NTE6400](#) [JANTX2N6796U](#) [JANTX2N6784U](#) [JANTXV2N5416U4](#) [SQM110N05-06L-GE3](#) [SIHF35N60E-GE3](#)